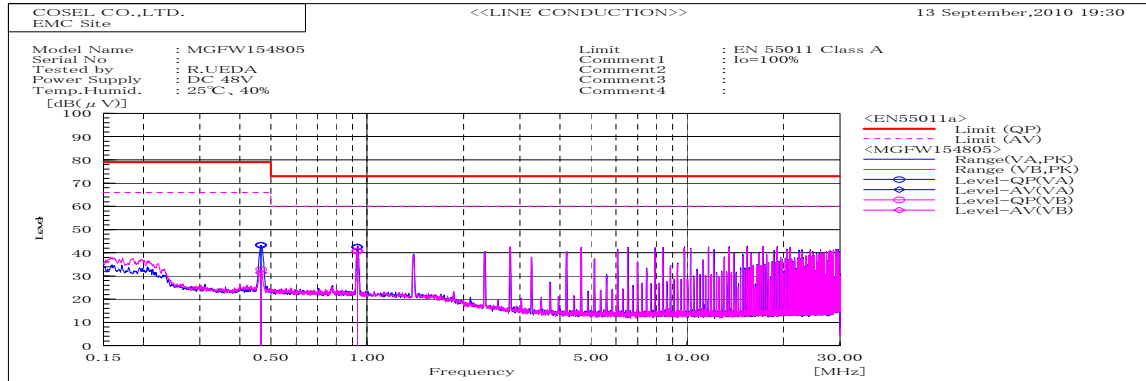
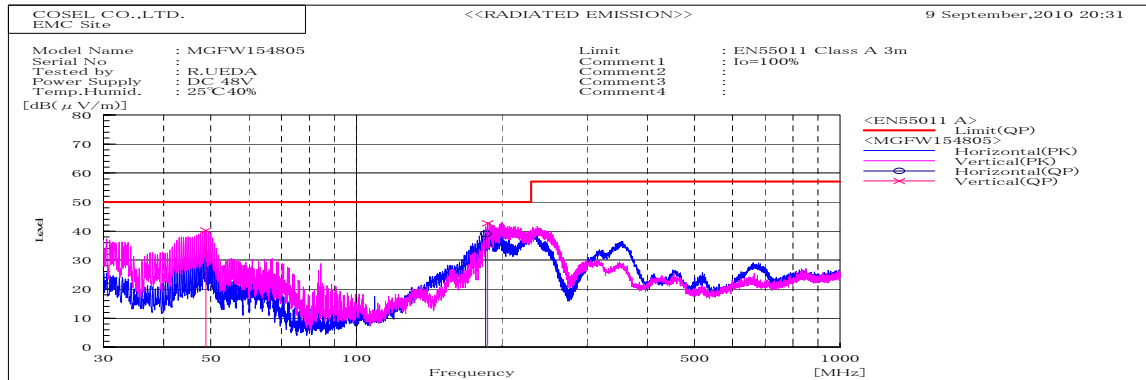


DATA SHEET

Model	MGFW154805	Date	21-Sep-10
Test	EMI	Temp.	25 degreeC
	Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.4656		VA	33.2	33.2	10.1	43.3	43.3	79	66	35.7	22.7	Pass	
0.46647		VB	22.8	21.4	10	32.8	31.4	79	66	46.2	34.6	Pass	
0.93113		VA	32.3	32.4	10.1	42.4	42.5	73	60	30.6	17.5	Pass	
0.93229		VB	30.7	30.7	10	40.7	40.7	73	60	32.3	19.3	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
48.833	V	Stable	63.4	-23.2	40.2	50	9.8	Pass	101	289	
185.175	H	Stable	61.3	-22.2	39.1	50	10.9	Pass	159	344	
186.981	V	Stable	64.8	-22.1	42.7	50	7.3	Pass	146	264	

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

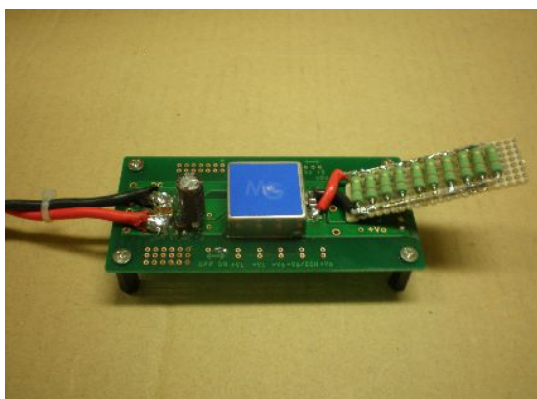


Conditions

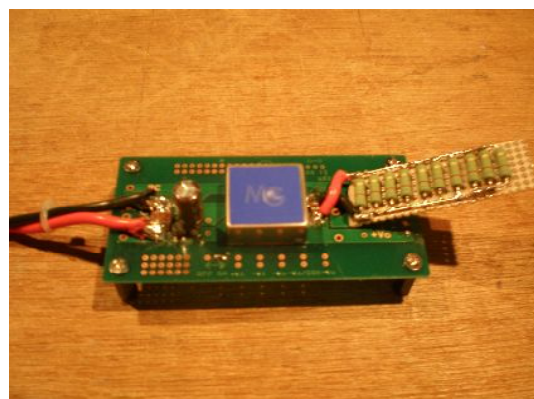
Test : EMI
Model Name : MGFS1548□□/MGFW1548□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

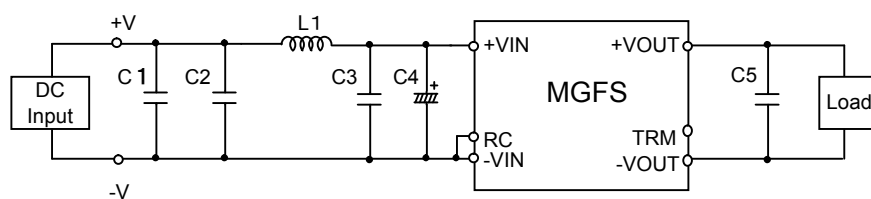


Fig.1 Testing circuitry 1

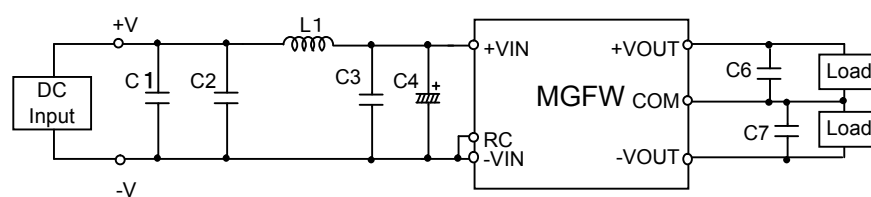


Fig.2 Testing circuitry 2

L1	: 10 μ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 μ F	C4532JB2A225MT (TDK)
C4	: 80V	47 μ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 μ F	CM32X5R226K25A (KYOCERA)